

Applicant: Mid Ocean Brands B.V.

Product: 3 port USB hub with dual input

Trademark: N/A

Model No.: MO6848

Test Standards: EN 55032:2015+A11:2020+A1:2020

EN IEC 61000-3-2:2019 +A1:2021

EN 55035:2017+A11:2020

EN 61000-3-3:2013+A2:2021+AC:2022-01

Test Result:

The EMC testing has been performed on the submitted

samples and found in compliance with council EMC Directive

2014/30/EU.

Approved By

Terry long

Terry Tang

Manager

Dated: July 07, 2023

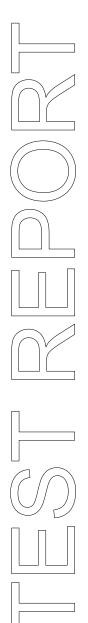
Results appearing herein relate only to the sample tested

The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel (755) 83448688, Fax (755) 83442996, E-Mail:info@timeway-lab.com



Date: 2023-07-07



Page 2 of 47

Special Statement:

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

The testing quality system of our laboratory meet with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

CNAS-LAB Code: L2292

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2017 General Requirements) for the Competence of testing Laboratories.

FCC-Registration No.: 744189

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 744189.

Industry Canada (IC) — Registration No.:5205A

The EMC Laboratory has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 5205A.

A2LA (Certification Number:5013.01)

The EMC Laboratory has been accredited by the American Association for Laboratory Accreditation (A2LA). Certification Number:5013.01

Report No.: TW2306389E

Date: 2023-07-07



TABLE OF CONTENT

	Test Report Conclusion	
	Special Statement	
	Content	
<u>1.0</u>	General Details	5
1.1.	Test Lab Details	5
1.2	Applicant Details	5
1.3	Description of EUT	5
1.4	Submitted Sample	5
1.5	Test Duration.	6
1.6	Additional Information of EUT.	6
1.7	Test Engineer & Verify Engineer.	6
<u>2.0</u>	List of Measurement Equipment	7
2.1	Conducted Emission Test.	7
2.2	Radiated Disturbance Test.	7
2.3	Harmonic& Flicker Test.	7
2.4	ESD Test	7
2.5	RF Field Strength Susceptibility.	7
2.6	Electrical Fast Transient/Burst (EFT/B) Immunity Test	8
2.7	Surge Test.	8
2.8	Conducted Immunity Test.	8
2.9	Power-Frequency Magnetic Field.	8
2.10	Voltage Dips/Interruption Immunity Test.	9
<u>3.0</u>	Technical Details	10
3.1	Investigations Requested.	10
3.2	Test Standards.	10
3.3	Performance Criteria.	10
3.4	Test Standards and Results Summary Tables.	11
<u>4.0</u>	Electromagnetic Interference Test Results	12
4.1	Power line Conducted Emission Test.	12
4.2	Telecommunication Ports Conducted Emission Test.	15
4.3	Radiated Disturbance Test.	18
4.4	Harmonic Current Emission Test.	21
4.5	Voltage Fluctuations &Flicker Test.	23

4.5

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Page 4 of 47

Report No.: TW2306389E

Date: 2023-07-07



<u>5.0</u>	Immunity Test	24
5.1	Electrostatic Discharge.	24
5.2	RF Field transients / Burst Immunity Test.	26
5.3	Electrical Fast Transient/Burst (EFT/B) immunity test.	28
5.4	Surge Test.	30
5.5	Conducted Immunity Test.	32
5.6	Power-Frequency Magnetic Field.	34
5.7	Voltage Dips / Interruptions Immunity Test.	36
<u>6.0</u>	Product Labeling	38
6.1	CE Mark label specification.	38
	Appendix	39

Date: 2023-07-07



Page 5 of 47

1.0 General Details

1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan

District, Shenzhen, China

Tel: +86 755 83448688 Fax :+86 755 83442996

Test Location

All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan

District, Shenzhen, China

Tel: +86 755 83448688 Fax: +86 755 83442996

1.2 Applicant Details

Applicant: Mid Ocean Brands B.V.

Address: 7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong.

Telephone: --Fax: ---

Manufacturer: Mid Ocean Brands B.V.

Address: 7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong.

Telephone: -Fax: --

1.3 Description of EUT

Product: 3 port USB hub with dual input

Trademark: N/A
Model Number: MO6848
Adding Trademark: N/A
Adding Model Number: N/A

Rating: 5V 0.5A

1.4 Submitted Sample(s)

1 Samples

The report refers only to the sample tested and does not apply to the bulk.

Page 6 of 47 Report No.: TW2306389E Date: 2023-07-07

1.5 Test Duration

Date of Receipt of Application: June 30, 2023 Date of Test: June 30, 2023 ~ July 07, 2023

1.6 Additional information of EUT

	Submitted	Not Available
User Manual	\boxtimes	
Part List		
Circuit Diagram		
Printed circuit board	\boxtimes	
[PCB] Layout		
Block Diagram		

1.7 Test Engineer

Les. Lan The sample(s) tested by

Print Name: Leo Lau/ Engineer

This test report is not valid without personnel's signatures of SHENZHEN TIMEWAY TESTING LABORATORIES.

Date: 2023-07-07



2.0 List of Measurement Equipment

2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS 30	834115/006	RS	2022.07.15	1Year
LISN	NNB42	00012	SCHAFFNER	2022.08.18	1Year

2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESPI 3	100379	RS	2022.07.15	1Year
Spectrum Analyzer	E4407B	MY50441392	HP/Agilent	2022.07.15	1Year
Amplifier	BBV9743	#218	HP/Agilent	2022.07.15	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2022.07.18	3Year
Horn Antenna	BBHA 9120D	9120D-631	RS	2022.07.18	3Year
Amplifier	8449B	3008A00160	HP/Agilent	2022.07.15	1Year

2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test					
System	PACS-1	72305	CI	2022.07.15	1Year
5K VA AC Power					
Source	5001iX	56060	CI	2022.07.15	N/A

2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2022.07.18	1Year

2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2022.07.15	1Year
Power Meter	NRVS		RS	2022.07.15	1Year
Voltage Probe	URV5-Z2	100012	RS	2022.07.15	1Year

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Date: 2023-07-07



Voltage Probe	URV5-Z2	100013	RS	2022.07.15	1Year
Power Amplifier	150W1000	300999	AR	2022.07.15	1Year
Power Amplifier	25S1G4AM1	305993	AR	2022.07.15	1Year
Field Probe	CBL6111C	2576	Holaday	2022.07.15	1Year
Bilog Antenna	MCDC		Chase	2022.07.15	1Year

2.6 Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2022.07.15	1Year
Power Source	MV2616	0104-14	EM TEST	2022.07.15	1Year

2.7 Surge Test

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Ultra Compact	UCS 500				
Simulator	M4	0304-42	EM TEST	2022.07.15	1Year
Power Source	MV2616	0104-14	EM TEST	2022.07.15	1Year

2.8 Conducted Immunity Test

					Calibration	Calibration
Name		Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous	Wave					
Simulator		CWS 500C	0407-05	EM TEST	2022.07.15	1 Year

2.9 Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave					
Simulator	UCS 500 M4	0304-42	EM TEST	2022.07.15	1 Year
Power Source					
Network	MV 2616	0104-14	EM TEST	2022.07.15	1 Year
Current Transformer	MC2630		EM TEST	2022.07.15	1 Year
Magnetic Coil	MS100	0304-42	EM TEST	2022.07.15	1 Year

Page 9 of 47 Report No.: TW2306389E

Date: 2023-07-07



2.10 Voltage Dips/Interruption Immunity Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact					
Simulator	UCS 500 M4	0304-42	EM TEST	2022.07.15	1Year
Power Source	MV2616	0104-14	EM TEST	2022.07.15	1Year

Date: 2023-07-07



Page 10 of 47

3.0 **Technical Details**

3.1 **Investigations Requested**

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility [EMS] tests for CE Marking

3.2 **Test Standards**

	Test Standards			
EN 55032:2015+A11:2020+A1:2020	Electromagnetic compatibility of multimedia equipment - Emission Requirements			
EN IEC 61000-3-2:2019+ A1:2021	Electromagnetic compatibility(EMC)- Part 3-2:Limits-Limits for harmonic current emissions(equipment input current ≤ 16A per phase)			
EN 61000-3-3:2013 +A2:2021+AC:2022-01	Electromagnetic compatibility (EMC)- Part 3-3:Limits-Limitation of voltage changes, Voltage fluctuations and flicker in public low-voltage supply systems. For equipment with rated current ≤ 16A per phase and not subject to conditional connection			
EN 55035:2017+A11:2020	Electromagnetic compatibili requirements	ty of multimedia equipment - Immunity		
	EN 61000-4-2:2009	Electrostatic discharge		
	EN IEC 61000-4-3:2020	RF electromagnetic field disturbances		
	EN 61000-4-4:2012	Electrical Fast transients		
	EN 61000-4-5:2014	Surge		
	EN 61000-4-6:2014 Conducted susceptibility			
	EN 61000-4-8:2010	Power-frequency Magnetic Field		
	EN IEC 61000-4-11: 2020	Dips/Voltage Interruption Variation		

3.3 **Performance Criteria**

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Page 11 of 47 Report No.: TW2306389E

Date: 2023-07-07



3.4 **Test standards and Results Summary Tables**

Test Condition	Test Requirement	Test Method	Test Result			
EMISSION Results Summary						
Conducted Emission on AC	EN 55032:2015	EN 55032:2015	Dogg			
Mains, 150kHz to 30MHz	+A11:2020+A1:2020	+A11:2020+A1:2020	Pass			
Conducted Emission on at	EN 55032:2015	EN 55032:2015				
telecommunication ports,	+A11:2020+A1:2020	+A11:2020+A1:2020	N/A			
150kHz to 30MHz						
Radiated Emissions,	EN 55032:2015	EN 55032:2015	Pass			
30MHz to 6GHz	+A11:2020+A1:2020	+A11:2020+A1:2020	Pass			
Harmonic Emissions on AC	EN IEC 61000-3-2:2019	EN IEC 61000-3-2:2019	N/A			
supply	+A1:2021	+A1:2021	IN/A			
Voltage fluctuations on AC	EN 61000-3-3:2013	EN 61000-3-3:2013	N/A			
supply	+A2:2021+AC:2022-01	+A2:2021+AC:2022-01	N/A			
	IMMUNITY Results Summ	nary				
Electrostatic Discharge	EN 55035:2017+A11:2020	EN 61000-4-2: 2009	Pass			
Continuous RF electromagnetic	EN 55035:2017+A11:2020	EN IEC 61000-4-3:2020	Pass			
field disturbances			1 ass			
Continuous induced RF	EN 55035:2017+A11:2020	EN 61000-4-6:2014	Pass			
disturbances						
Power frequency magnetic field	EN 55035:2017+A11:2020	EN 61000-4-8: 2010	N/A			
Electrical fast transients/burst	EN 55035:2017+A11:2020	EN 61000-4-4: 2012	Pass			
(EFT/B)						
Surges	EN 55035:2017+A11:2020	EN 61000-4-5: 2014	Pass			
Voltage dips and interruptions	EN 55035:2017+A11:2020	EN IEC 61000-4-11: 2020	Pass			
Broadband impulsive conducted	EN 55035:2017+A11:2020	EN 61000-4-6:2014	N/A			
disturbances						

Note: N/A-Not applicable

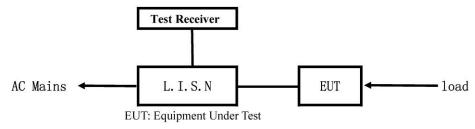
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4.0 Electromagnetic Interference Test results

4.1 Power line Conducted Emission Test

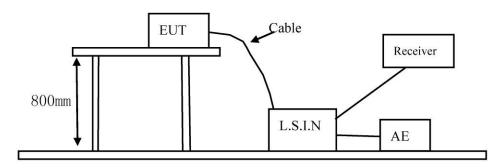
4.1.1 Schematics of the test



4.1.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.1.3 Power line conducted Emission Limit

	Limits dB(µ V)					
Frequency(MHz)	Class A F	Equipment	Class B Equipment			
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level		
0.15 ~ 0.50	79.0	66.0	66.0~56.0*	56.0~46.0*		
0.50 ~ 5.00	73.0	60.0	56.0	46.0		
5.00 ~ 30.00	73.0	60.0	60.0	50.0		

Notes: 1. *decreasing linearly with logarithm of frequency.

2. The lower limit shall apply at the transition frequencies

4.1.4 Test Results

Limits for Conducted Emission test, please refer to limit line (Quasi-peak) and Average in the following diagram labelled as (QP)&AV

Remark: Calculated measurement uncertainty=3.6dB

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A: Disturbance Voltage Limits at mains on Live terminals (150kHz to 30MHz)

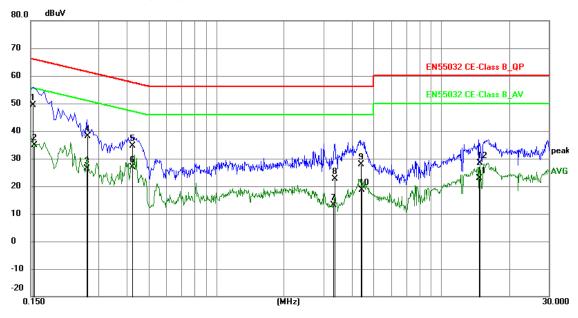
EUT Operating Environment

Temperature: 25°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: USB Power: AC230V/50Hz Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F
1	0.1539	39.56	9.78	49.34	65.79	-16.45	QP	Р
2	0.1550	24.98	9.78	34.76	55.73	-20.97	AVG	Р
3	0.2660	16.64	9.75	26.39	51.24	-24.85	AVG	Р
4	0.2680	28.42	9.75	38.17	61.18	-23.01	QP	Р
5	0.4250	24.98	9.76	34.74	57.35	-22.61	QP	Р
6	0.4250	17.15	9.76	26.91	47.35	-20.44	AVG	Р
7	3.3240	3.17	9.86	13.03	46.00	-32.97	AVG	Р
8	3.3560	12.76	9.86	22.62	56.00	-33.38	QP	Р
9	4.4020	17.87	9.90	27.77	56.00	-28.23	QP	Р
10	4.4090	8.67	9.90	18.57	46.00	-27.43	AVG	Р
11	14.7470	12.50	10.37	22.87	50.00	-27.13	AVG	Р
12	14.7800	18.08	10.37	28.45	60.00	-31.55	QP	Р

Date: 2023-07-07



B: Disturbance Voltage Limits at mains on Neutral terminals (150kHz to 30MHz)

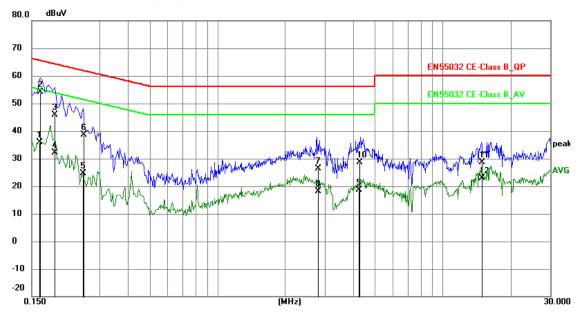
EUT Operating Environment

Temperature: 25°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: USB Power: AC230V/50Hz Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



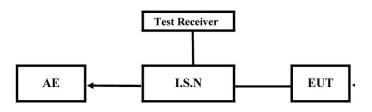
No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F
1	0.1620	26.22	9.78	36.00	55.36	-19.36	AVG	Р
2	0.1630	44.24	9.78	54.02	65.31	-11.29	QP	Р
3	0.1900	36.15	9.76	45.91	64.04	-18.13	QP	Р
4	0.1900	22.31	9.76	32.07	54.04	-21.97	AVG	Р
5	0.2530	14.76	9.75	24.51	51.66	-27.15	AVG	Р
6	0.2540	28.88	9.75	38.63	61.63	-23.00	QP	Р
7	2.7920	16.56	9.83	26.39	56.00	-29.61	QP	Р
8	2.7969	8.36	9.83	18.19	46.00	-27.81	AVG	Р
9	4.2399	8.79	9.90	18.69	46.00	-27.31	AVG	Р
10	4.2840	18.61	9.90	28.51	56.00	-27.49	QP	Р
11	14.8480	18.16	10.37	28.53	60.00	-31.47	QP	Р
12	14.8570	12.61	10.37	22.98	50.00	-27.02	AVG	Р

Date: 2023-07-07



4.2 **Telecommunication ports Conducted Emission Test**

4.2.1 **Schematics of the test**

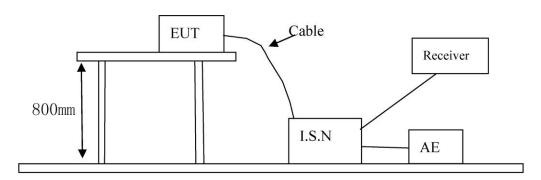


EUT: Equipment Under Test

4.2.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.2.3 Telecommunication ports conducted Emission Limit

	Class A Limits				Class B Limits			
Frequency	Quasi-peak Level A		Average Level		Quasi-peak Level		Average Level	
(MHz)	Voltage dB(uV)	Current dB(uA)	Voltage dB(uV)	Current dB(uA)	Voltage dB(uV)	Current dB(uA)	Voltage dB(uV)	Current dB(uA)
0.15 ~ 0.50	97 to 87	53 to 43	87 to 74	40 to 30	84 to 74	40 to 30	74 to 64	30 to 20
0.50 ~ 30.00	87	43	74	30	74	30	64	20

- Notes: 1.*decreasing linearly with logarithm of frequency.
 - 2. The tighter limit shall apply at the transition frequencies

4.2.4 Test Results: N/A

Limits for Conducted Emission test, please refer to limit line (Quasi-peak) and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=1.9dB

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Date: 2023-07-07



Page 16 of 47

Conducted Emission on Telecommunication port (150kHz to 30MHz) A:

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBμV)		Limit(dBµV)	
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average

Date: 2023-07-07



Page 17 of 47

B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBμA)		Limit(dBµA)	
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average

Note: This test item is not applicable because there is no telecommunication port

Date: 2023-07-07



4.3 Radiated Disturbance Test

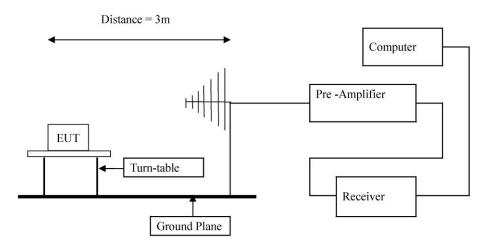
4.3.1 Schematics of the test



4.3.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB μ V/m)		
	Class A Limits	Class B Limits	
0-230	50.00	40.00	
230-1000	57.00	47.00	
1000-3000	56(AV)/76(PK)	50(AV)/70(PK)	
3000-6000	60(AV)/80(PK)	54(AV)/74(PK)	

Note: The lower limit shall apply at the transition frequencies

4.3.4 Test result

Limits for Radiated Disturbance test, please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

Remark:

Calculated measurement uncertainty=4.7dB

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Report No.: TW2306389E Page 19 of 47

Date: 2023-07-07



A: Radiated Disturbance (30MHz----1000MHz)

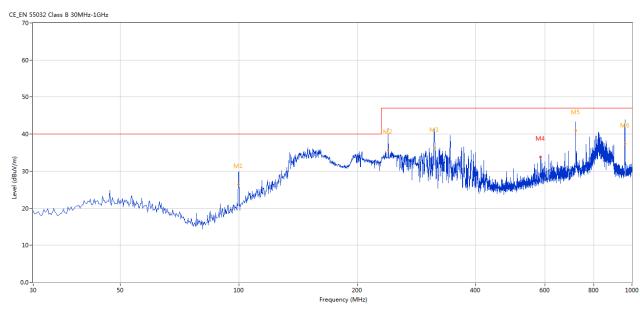
Project Number: CASE3 Test Time: 2023-07-07_18.37.33

EUT Name: 3 port USB hub with dual input Test Engineer: STEPHEN Manufacturer: Mid Ocean Brands B.V. Test Standard: EN55032

Model: MO6848 Work Addition: USB

 Temp.(oC):
 25
 Load:

 Hum.:
 65%
 Charger:



No.	Frequency	Results	Factor	Limit	Margin	Detector	Table	Height	Antenna	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	(dB)		(Degree)	(cm)		
1	99.823	29.57	-13.56	40.0	10.43	Peak	267.00	100	Horizontal	Pass
1*	99.823	26.44	-13.56	40.0	13.56	QP	267.00	100	Horizontal	Pass
2	239.953	42.56	-12.33	47.0	4.44	Peak	267.00	100	Horizontal	Pass
2*	239.953	35.67	-12.33	47.0	11.33	QP	267.00	100	Horizontal	Pass
3	314.381	42.48	-10.85	47.0	4.52	Peak	273.00	100	Horizontal	Pass
3*	314.381	36.15	-10.85	47.0	10.85	QP	273.00	100	Horizontal	Pass
4	586.156	33.78	-5.50	47.0	13.22	Peak	307.00	100	Horizontal	Pass
5	719.983	43.26	-4.06	47.0	3.74	Peak	298.00	100	Horizontal	Pass
5*	719.983	40.94	-4.06	47.0	6.06	QP	298.00	100	Horizontal	Pass
6	959.755	44.26	-1.63	47.0	2.74	Peak	249.00	100	Horizontal	Pass
6*	959.755	37.37	-1.63	47.0	9.63	QP	249.00	100	Horizontal	Pass

Page 20 of 47

Report No.: TW2306389E

Date: 2023-07-07



B: Radiated Disturbance (30MHz----1000MHz)

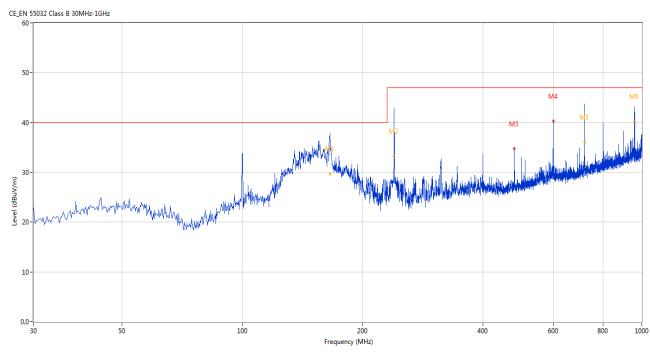
Project Number: CASE3 Test Time: 2023-07-07_18.37.33

EUT Name: 3 port USB hub with dual input Test Engineer: STEPHEN Manufacturer: Mid Ocean Brands B.V. Test Standard: EN55032

Model: MO6848 Work Addition: USB

 Temp.(oC):
 25
 Load:

 Hum.:
 65%
 Charger:



No.	Frequency	Results	Factor	Limit	Margin	Detector	Table	Height	Antenna	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	(dB)		(Degree)	(cm)		
1	165.705	38.44	-16.16	40.0	1.56	Peak	324.00	107	Vertical	Pass
1*	165.705	29.61	-16.16	40.0	10.39	QP	324.00	107	Vertical	Pass
2	240.001	43.88	-12.33	47.0	3.12	Peak	222.00	193	Vertical	Pass
2*	240.001	33.21	-12.33	47.0	13.79	QP	222.00	193	Vertical	Pass
3	479.240	34.72	-7.45	47.0	12.28	Peak	265.00	100	Vertical	Pass
4	599.975	40.28	-4.95	47.0	6.72	Peak	334.00	100	Vertical	Pass
5	719.997	44.54	-4.06	47.0	2.46	Peak	268.00	200	Vertical	Pass
5*	719.997	36.10	-4.06	47.0	10.90	QP	268.00	200	Vertical	Pass
6	959.140	43.32	-1.64	47.0	3.68	Peak	277.00	134	Vertical	Pass
6*	959.140	40.14	-1.64	47.0	6.86	QP	277.00	134	Vertical	Pass

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Page 21 of 47

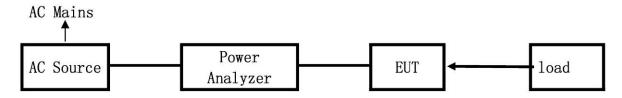
Report No.: TW2306389E

Date: 2023-07-07



4.4 **Harmonic Current Emission Test**

4.4.1 **Schematic of the test**

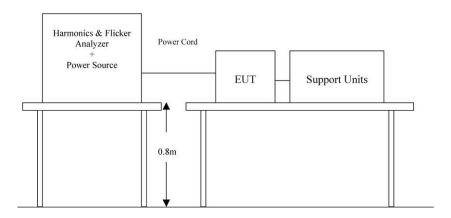


EUT: Equipment Under Test

4.4.2 Test Method:

The test was performed in accordance with EN IEC 61000-3-2:2019+A1:2021

Block diagram of Test setup



Limits of Harmonic Current Emission For Class A

Date: 2023-07-07



Harmonic order	Maximum permissible harmonic current
n	A
Odd har	monics
3	2,30
5	1,14
7	0,77
9	0,40
11	0,33
13	0,21
15 ≤ n ≤ 39	0,15 <u>15</u>
Even har	monics
2	1,08
4	0,43
6	0,30
8 ≤ n ≤ 40	0,23 <u>8</u>

4.4.4 Test Results

Please refer to the following pages

Harmonic Current Emission Test

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 kPa

EUT set Condition:

Results: N/A

N/A ---EUT powered by AA battery, this test item not applicable

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Lim t)%		result/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

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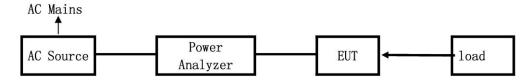
Report No.: TW2306389E Page 23 of 47

Date: 2023-07-07



4.5 Voltage Fluctuations & Flicker Test

4.5.1 Schematic of the test

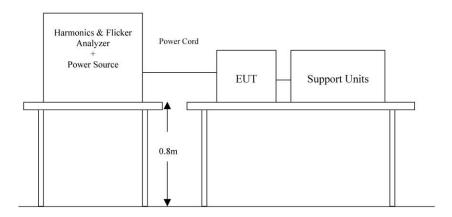


EUT: Equipment Under Test

4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013+A2:2021+AC:2022-01

Block diagram of Test setup



4.5.3 Test Results

Result: N/A

Note: EUT powered by AA battery, this test item not applicable

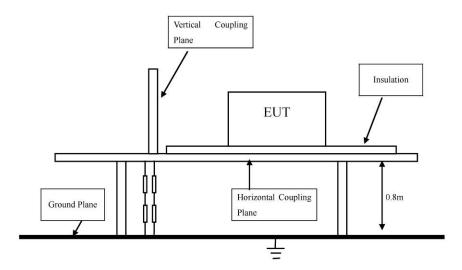
Date: 2023-07-07



5.0 Immunity Test

5.1 Electrostatic Discharge

5.1.1 Schematic of the test



5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

5.1.3 Test severity

±4kV for direct & in-direct Contact Discharge

 ± 8 kV for air Discharge

Performance Criterion Require: **B** (Please see following table)

5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
B Degradation of performance allowed during the test the EUT returnment intended operation after the test.	
C Loss of function allowed during the test, provided that function is se recoverable or can be recovered by operation of controls.	

Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (kV)	discharge(kV)
1	$\pm 2 \mathrm{kV}$	±2kV
2	±4kV	$\pm 4 \mathrm{kV}$
3	$\pm 6 \mathrm{kV}$	$\pm 8 \mathrm{kV}$
4	$\pm 8 \mathrm{kV}$	±15kV

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Date: 2023-07-07



Page 25 of 47

5.1.5 Test Result

EUT Operating Environment

Temperature: 25 °C Humidity: 53%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
HCP (Horizontal coupling plane)	In-Direct	$\pm 2kV, \pm 4kV$	Pass
VCP (Vertical Coupling plane)	In-Direct	$\pm 2kV, \pm 4kV$	Pass
USB Port	Contact Discharge	$\pm 2kV, \pm 4kV$	Pass
Enclosure	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Panel	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
CABLE	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

Remark: Calculated measurement uncertainty= 0.2kV

Date: 2023-07-07



5.2 RF field strength susceptibility (80MHz-1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz)

5.2.1 Schematics of the test



EUT: Equipment Under Test

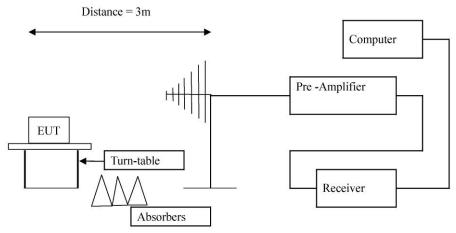
5.2.2 Test Method:

The test was performed in accordance with EN IEC 61000-4-3:2020

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description			
A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.				
B Degradation of performance allowed during the test the EUT retuintended operation after the test.				
C Loss of function allowed during the test, provided that function i recoverable or can be recovered by operation of controls.				

Severity Level

Level	Field Strength (V/m)
1	1
2	3
3	10

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Report No.: TW2306389E Page 27 of 47

Date: 2023-07-07



5.2.4 Test Result:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Frequency	Face	P larity	Level	Dwell	Sweep	Results
(MHz)			(V/m	Time/s)	Rate (%)	
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass
1800,	0°	Horizontal	3	1	1	Pass
2600,	90°	Horizontal	3	1	1	Pass
3500,	180°	Horizontal	3	1	1	Pass
5000	270°	Horizontal	3	1	1	Pass
1800,	0°	Vertical	3	1	1	Pass
2600,	90°	Vertical	3	1	1	Pass
3500,	180°	Vertical	3	1	1	Pass
5000	270°	Vertical	3	1	1	Pass

Date: 2023-07-07



5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

5.3.1 Schematics of the test



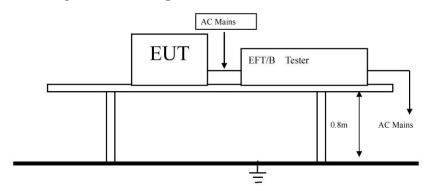
5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: **B** (Please see following table)

Block diagram of Test setup



5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description		
A No change in operational mode or degradation of performance outside o specification and no change in stored parameters.			
B Degradation of performance allowed during the test the EUT retuintended operation after the test.			
C Loss of function allowed during the test, provided that function recoverable or can be recovered by operation of controls.			

Severity Level

	Open Circuit output Test Voltag	e ±10%
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

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Report No.: TW2306389E Page 29 of 47

Date: 2023-07-07



5.3.4 Test Results

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Inject location: AC mains

Inject Line	Voltage	Inject	Method	Results
	kV	Times (s)		
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

Note: EUT powered by AA battery, this test item not applicable

Page 30 of 47

Report No.: TW2306389E

Date: 2023-07-07



5.4 Surge test

5.4.1 Schematics of the test



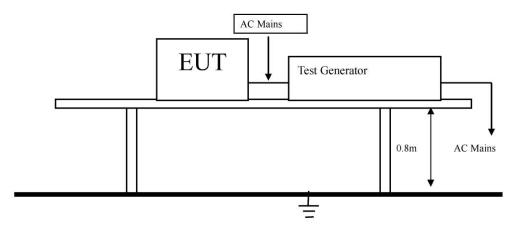
5.4.2 Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Page 31 of 47 Report No.: TW2306389E

Date: 2023-07-07



Severity Level

Severity Level	Open-Circuit Test Voltage
	kV
1	0.5
2	1.0
3	2.0
4	4.0
*	Special

5.4.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Test location:

Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
L-N	+	90	5	1.0	Pass
L-IN	-	270	5	1.0	Pass

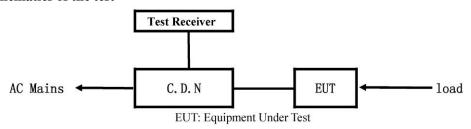
Note: EUT powered by AA battery, this test item not applicable

Date: 2023-07-07



5.5 Conducted Immunity test

5.5.1 Schematics of the test



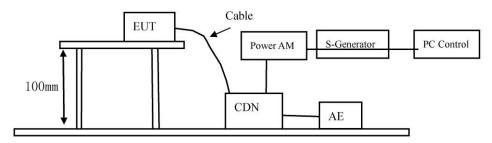
5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2014

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Voltage Level (e.m.f) V
1	1
2	3
3	10
*	Special

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Date: 2023-07-07



Page 33 of 47

5.5.4 Test Results:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following table for individual results.

Frequency	Injected Position	Strength	Criterion	Result
Range (MHz)				
0.15 - 10	AC Line	3V (rms)	A	Pass
10 - 30	AC Line	3 to 1V (rms)	A	Pass
30 - 80	AC Line	1V (rms)	A	Pass

Note: the amplitude of a test level varies over a given frequency range, it changes linearly with respect to the logarithm of the frequency

Note: EUT powered by AA battery, this test item not applicable

Date: 2023-07-07



5.6 Power-Frequency magnetic field test

5.6.1 Schematics of the test



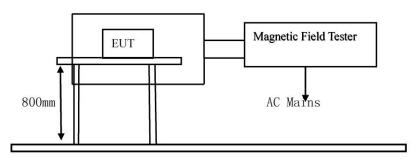
5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
*	Special

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Date: 2023-07-07



Page 35 of 47

5.6.4 Test Results:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Test Level	Testing Duration	Coil Orientation	Criterion	Result
1A/m	5 Mins	X	A	N/A
1A/m	5 Mins	Y	A	N/A
1A/m	5 Mins	Z	A	N/A

Page 36 of 47

Report No.: TW2306389E

Date: 2023-07-07



5.7 Voltage Dips/Interruptions immunity test

5.7.1 Schematics of the test

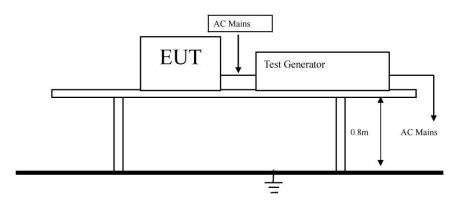


5.7.2 Test Method:

The test was performed in accordance with EN IEC 61000-4-11: 2020

Performance Criterion Require: C&B (Please see following table)

Block diagram of Test setup



5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Report No.: TW2306389E Page 37 of 47

Date: 2023-07-07



Severity Level

	Test Level %Ut	Reduction	Duration	Performance		
Voltage			(Periods)	Criteria		
Dip	<5	>95	0.5	В		
	70	30	25	С		
	·					
V-14	Test Level %Ut	Reduction	Duration	Performance		
Voltage Interceptions			(Periods)	Criteria		
	<5	>95	250	C		

5.7.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Voltage Dip:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	0.5	0° - 360°	В	Pass
70	30	25	0° - 360°	С	Pass

Voltage Interceptions:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° -360°	С	Pass

Note: EUT powered by AA battery, this test item not applicable

Report No.: TW2306389E Page 38 of 47

Date: 2023-07-07



6.0 Product Labelling

6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

Date: 2023-07-07



Page 39 of 47

Appendix:

Conducted Emissions



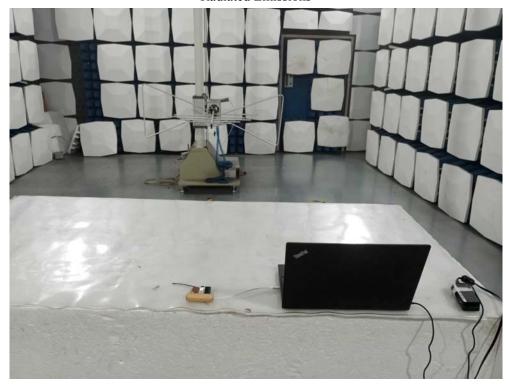
Report No.: TW2306389E Page 40 of 47

Date: 2023-07-07



Appendix:

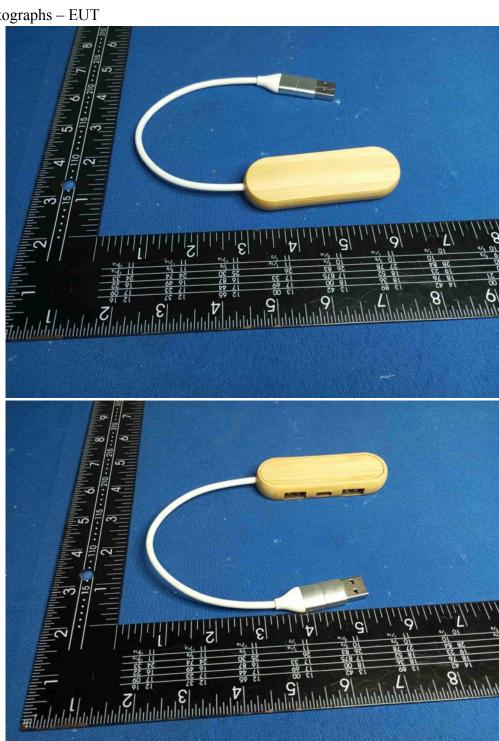
Radiated Emissions



Date: 2023-07-07



Photographs – EUT



The report refers only to the sample tested and does not apply to the bulk.

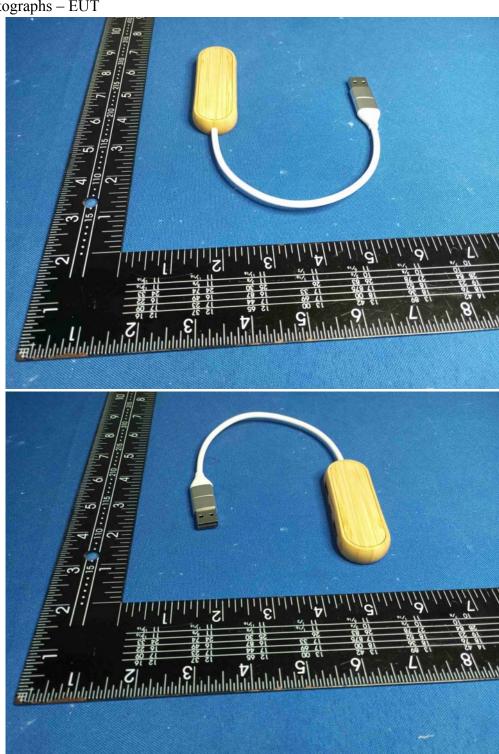
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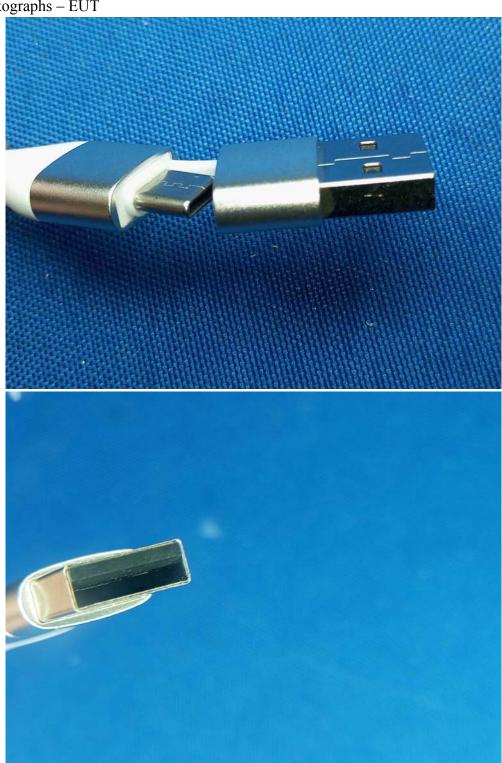
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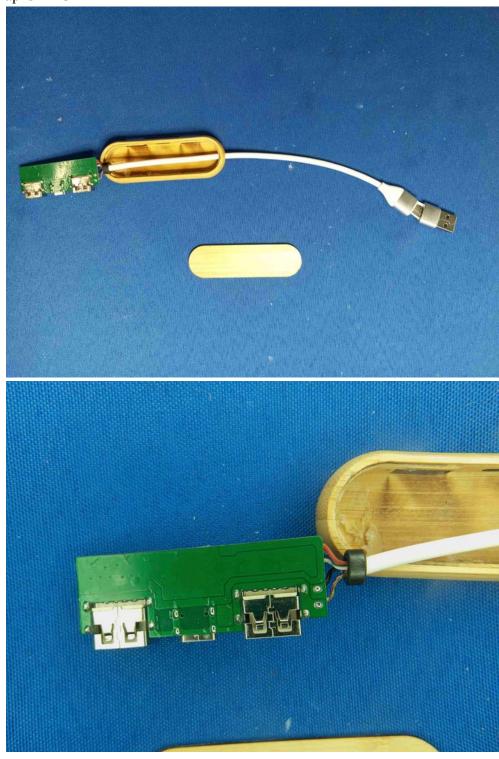
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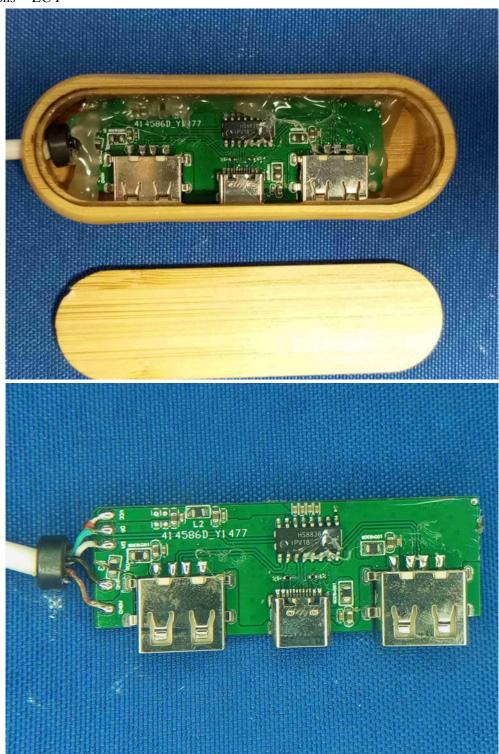
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-End of the report-

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